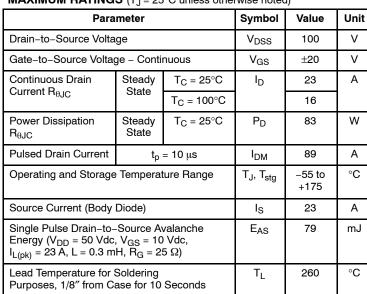
# **MOSFET** – Power, **N-Channel 100 V, 23 A, 55 m**Ω

## Features

- Low R<sub>DS(on)</sub>
- High Current Capability
- 100% Avalanche Tested
- NVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant



MAXIMUM RATINGS (T<sub>.1</sub> = 25°C unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Мах	Unit
Junction-to-Case (Drain) Steady State	$R_{\theta JC}$	1.8	°C/W
Junction-to-Ambient (Note 1)	$R_{\theta JA}$	39	

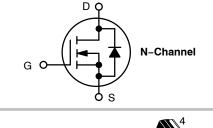
1. Surface mounted on FR4 board using 1 sq in pad size, (Cu Area 1.127 sq in [2 oz] including traces).



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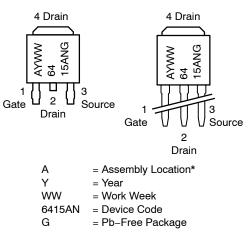
#### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX (Note 1)
100 V	55 mΩ @ 10 V	23 A





#### MARKING DIAGRAM **& PIN ASSIGNMENTS**



\* The Assembly Location code (A) is front side optional. In cases where the Assembly Location is stamped in the package, the front side assembly code may be blank.

### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 5 of this data sheet.

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, $I_D$ = 250 $\mu$ A		100			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				113		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 100 V	T <sub>J</sub> = 25°C T <sub>J</sub> = 125°C			1.0 100	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS}$ = 0 V, $V_{GS}$ =	±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 2$	250 μA	2.0		4.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				7.6		mV/°C
Drain-to-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> =	23 A		47	55	mΩ
Forward Transconductance	9 <sub>FS</sub>	$V_{GS}$ = 5 V, I <sub>D</sub> =	10 A		13		S
CHARGES, CAPACITANCES AND GA	TE RESISTANC	E					
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MHz, V <sub>DS</sub> = 25 V			700		pF
Output Capacitance	C <sub>OSS</sub>				110		
Reverse Transfer Capacitance	C <sub>RSS</sub>				52		
Total Gate Charge	Q <sub>G(TOT)</sub>				29		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 80 V, $I_{D}$ = 23 A			1.2		
Gate-to-Source Charge	Q <sub>GS</sub>				5		
Gate-to-Drain Charge	Q <sub>GD</sub>				14.6		
Plateau Voltage	V <sub>GP</sub>				5.7		V
Gate Resistance	R <sub>G</sub>				2.3		Ω
SWITCHING CHARACTERISTICS (Not	e 4)					•	•
Turn–On Delay Time	t <sub>d(on)</sub>				10		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V, V <sub>DD</sub> =	= 80 V,		37		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_{\rm D} = 23$ A, $R_{\rm G} = 6.1 \Omega$			30		
Fall Time	t <sub>f</sub>				37		
DRAIN-SOURCE DIODE CHARACTER	RISTICS						
Forward Diode Voltage	V <sub>SD</sub>		$T_J = 25^{\circ}C$		0.83	1.2	V
		$V_{GS} = 0 V, I_{S} = 23 A$	T <sub>J</sub> = 125°C		0.68		1
Reverse Recovery Time	t <sub>RR</sub>		·		65		ns
Charge Time	T <sub>a</sub>	$V_{GS}$ = 0 V, dI_S/dt = 100 A/µs, I_S = 23 A			46		1
Discharge Time	Т <sub>b</sub>				19		1
					1		

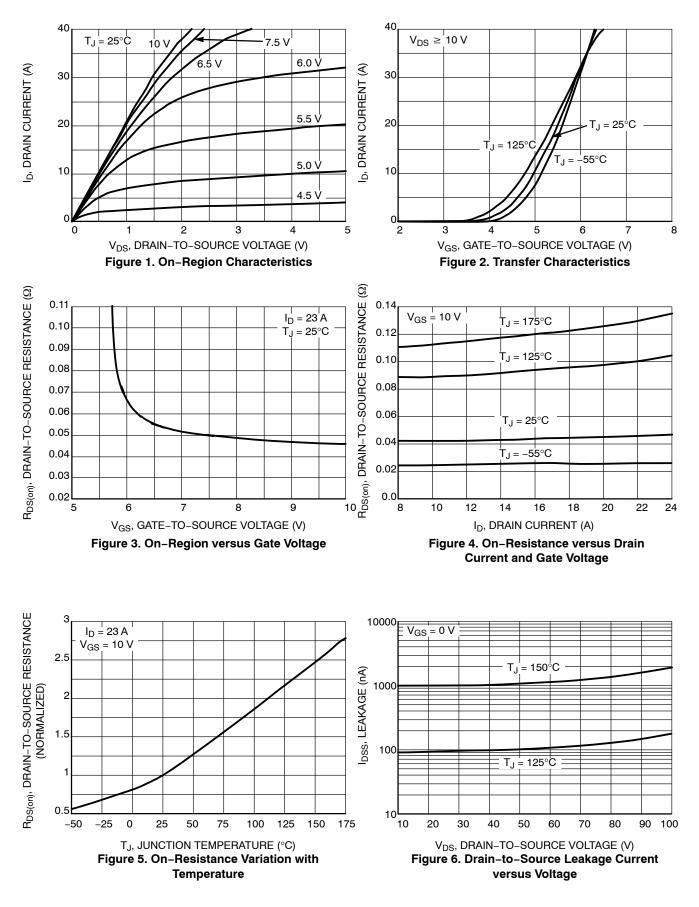
#### ELECTRICAL CHARACTERISTICS (T = 25°C unless otherwise noted)

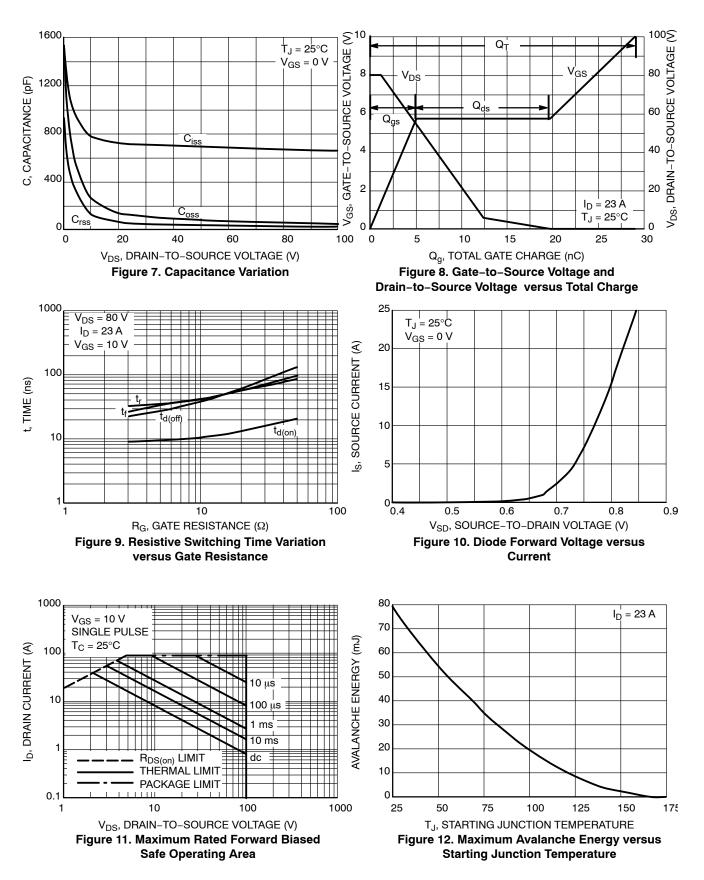
 $\mathsf{Q}_{\mathsf{R}\mathsf{R}}$ Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 2. Surface mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces). 3. Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

176

nC

Reverse Recovery Charge





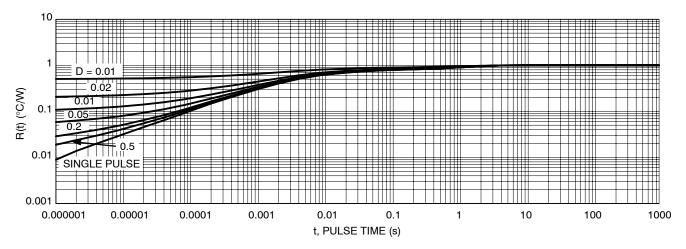


Figure 13. Thermal Response

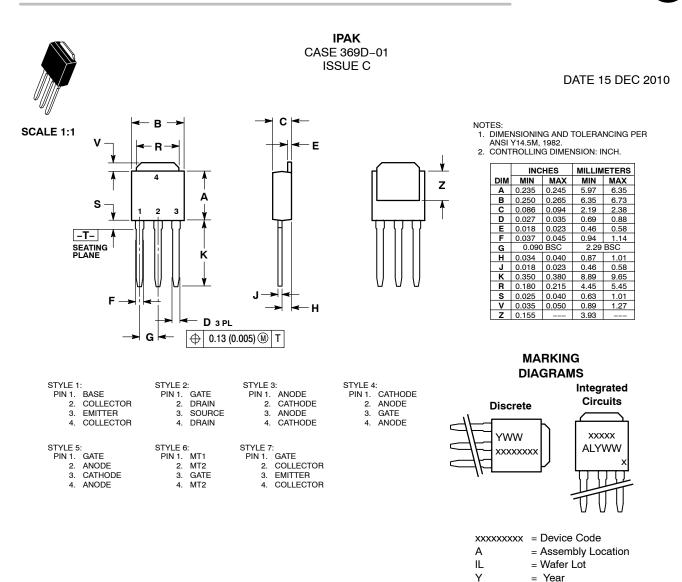
#### **ORDERING INFORMATION**

Device	Package	Shipping†
NTD6415ANT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTD6415AN-1G	IPAK (Pb-Free)	75 Units / Rail
NVD6415ANT4G*	DPAK (Pb-Free)	2500 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

\*NVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable.

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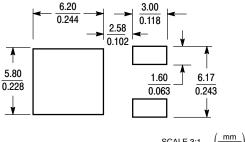
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1

L3

L4



\*For additional information on our Pb-Free strategy and soldering

SCALE 3:1

Inches

details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

# DATE 03 JUN 2010

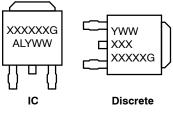
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

**ON Semiconductor** 

- 2. CONTROLLING DIMENSION: INCHES. 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-
- THERMAL FAD CONTOR OF FIGURE WITHIN DEMONSIONS b3, L3 and Z.
  DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL
- NOT EXCEED 0.006 INCHES PER SIDE 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM

	INCHES		MILLIMETER	
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
q	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
c	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
Е	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29	BSC
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108	REF	2.74 REF	
L2	0.020	BSC	0.51 BSC	
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Ζ	0.155		3.93	

# **MARKING DIAGRAM\***



= Device Code = Assembly Location L = Wafer Lot Y = Year = Work Week WW G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking.

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